





TOPAZ 64 & TFM FMC Technology

2019 March

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Introduction



- PA UT is a mature and accepted technology in Power Generation, Oil & Gas, Aerospace, Heavy Industry, ...
- The next technological step is FMC (Full Matrix Capture) and TFM (Total Focusing Method)
- Zetec's new TOP⁴Z⁶⁴ includes FMC and TFM technology
- Experimental validation of the improvements in flaw detection and characterization capability is essential for industry adoption.

Overview



- Principles of TFM & FMC
- FMC Data & Offline Processing
- Data Quantity & Inspection Strategy
- TFM Codes
- Topaz 64
- Case studies : HIC, HTHA, thick vessel welds, dissimilar metal welds
- Conclusions



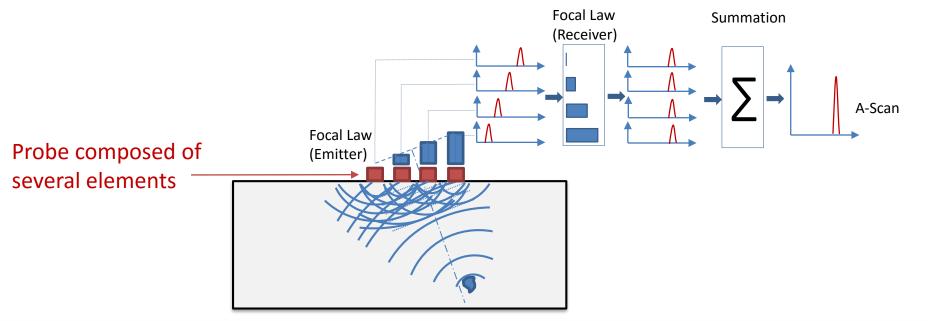


Principles of TFM & FMC

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Principles of the Standard Phased Array

- The instrument pulses every relevant probe element, using the delay defined by the focal law.
- Energy from each probe element is summed together, creating constructive and destructive interference

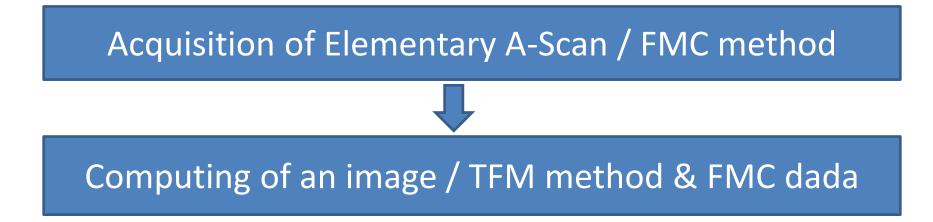


- The instrument digitizes signal received back on each relevant probe element and performs a summation of signals according the focal law.
- The end result is a summed and digitized A-Scan
- This Process is repeated for every focal law (angle, aperture) to generate a Sector Scan or Linear Scan. Raw signals are not saved

Principles of TFM (Imaged Focused on any points)



It's a 2 steps Process



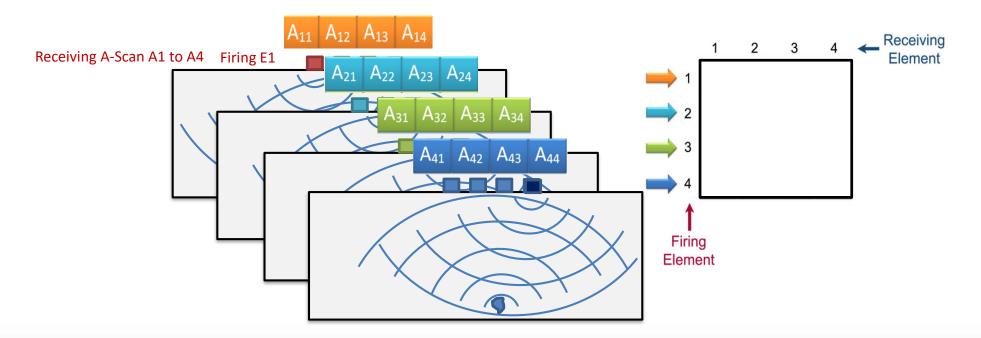
This global process can be real-time or off line

- Elementary A-Scan: A-Scan signal from receiving element,
- FMC: Full Matrix Capture, method for collecting of elementary A-Scans.
- TFM: Total Focusing Method

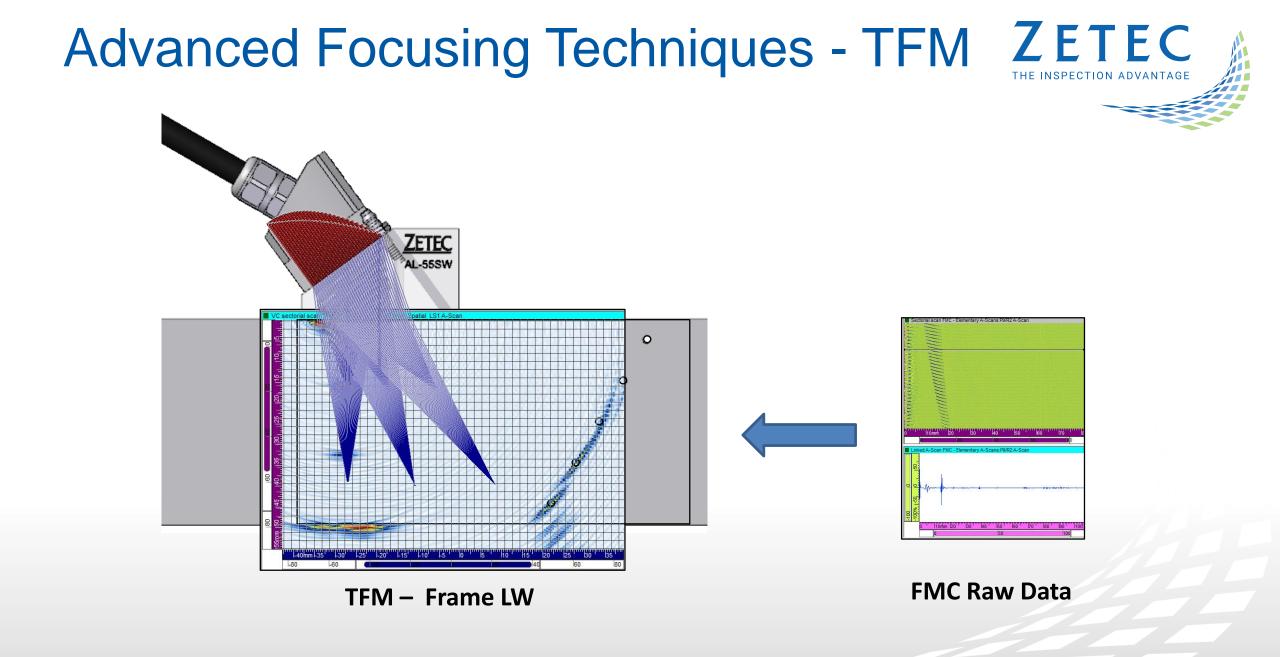
FMC (Full Matrix Capture)

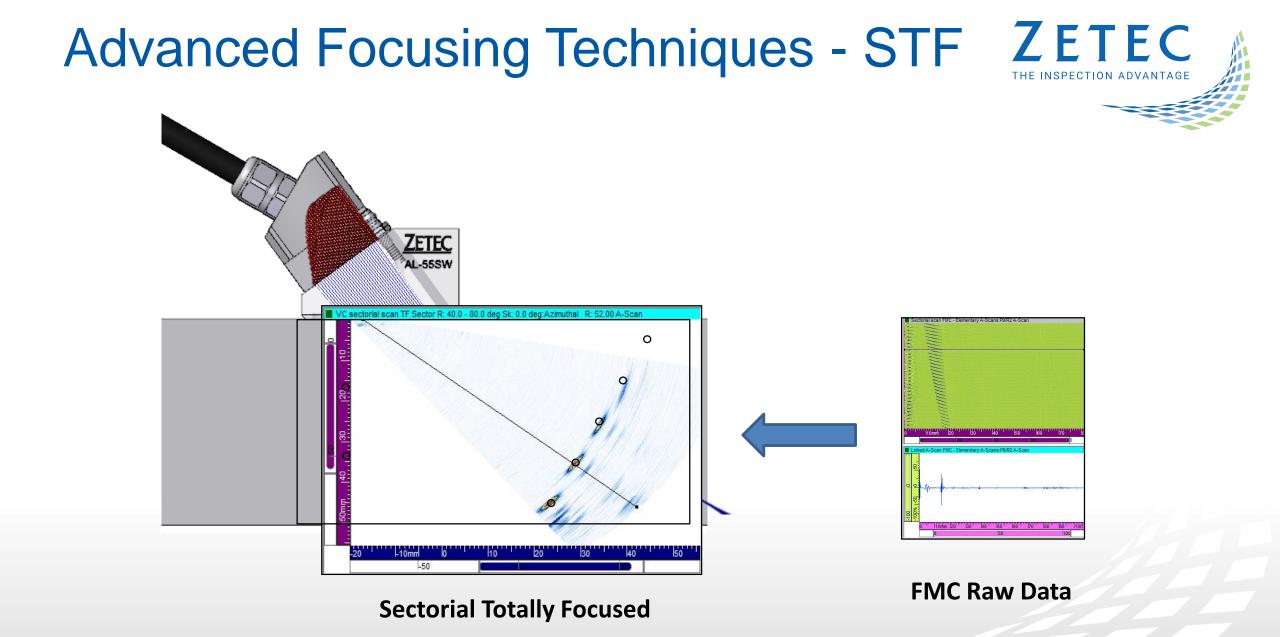


Full Matrix Capture (FMC) consists of *capturing and recording A-Scan signals from every transmitter-receiver pair* in the array



From raw A-scan it is possible to generate UT imaging for *any given focal law / beam* (aperture, angle, focus depth), and for *improved algorithms (e.g. TFM)* through *post processing*

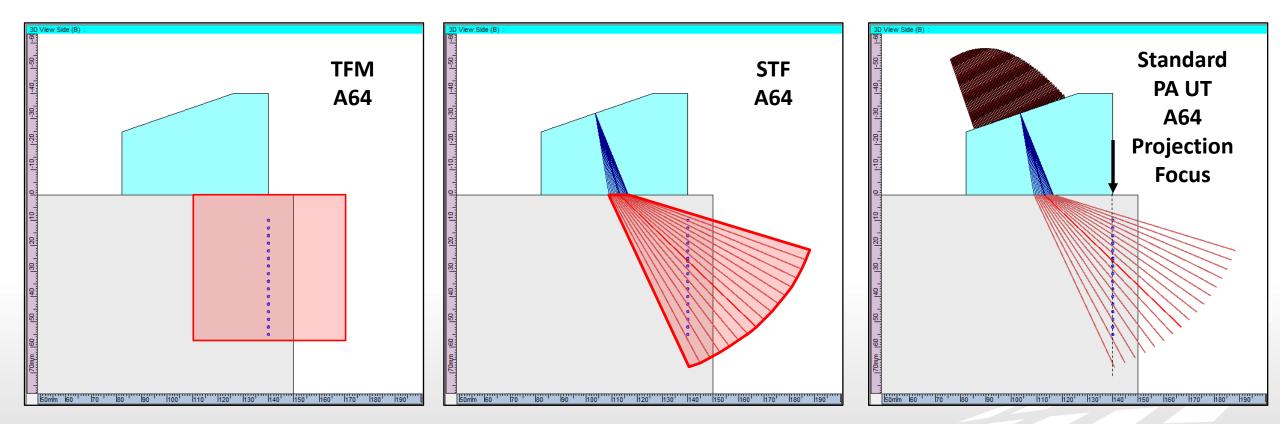




Benefits of Advanced Focusing Techniques ZETEC

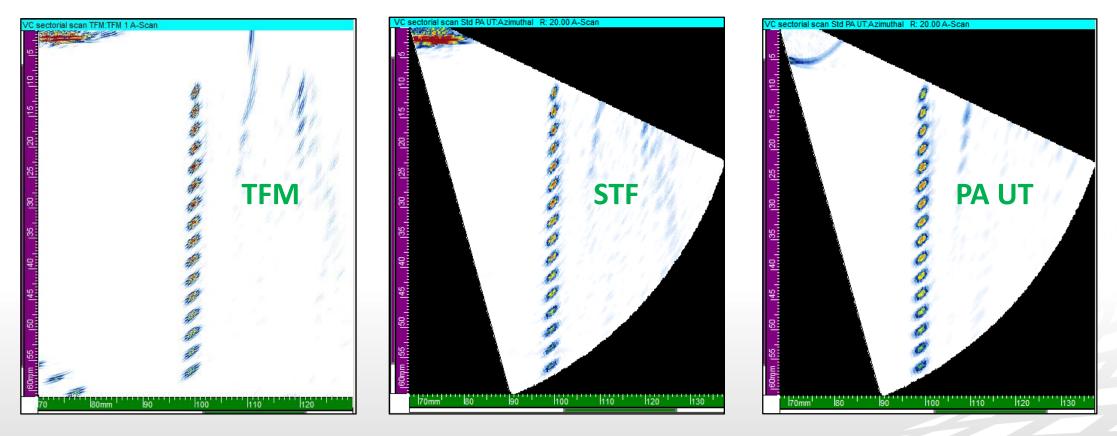
5 MHz linear array, 64 elements, LW wedge on Ø 1 mm SDH

Comparison of focusing capability, TFM, STF versus standard PA UT

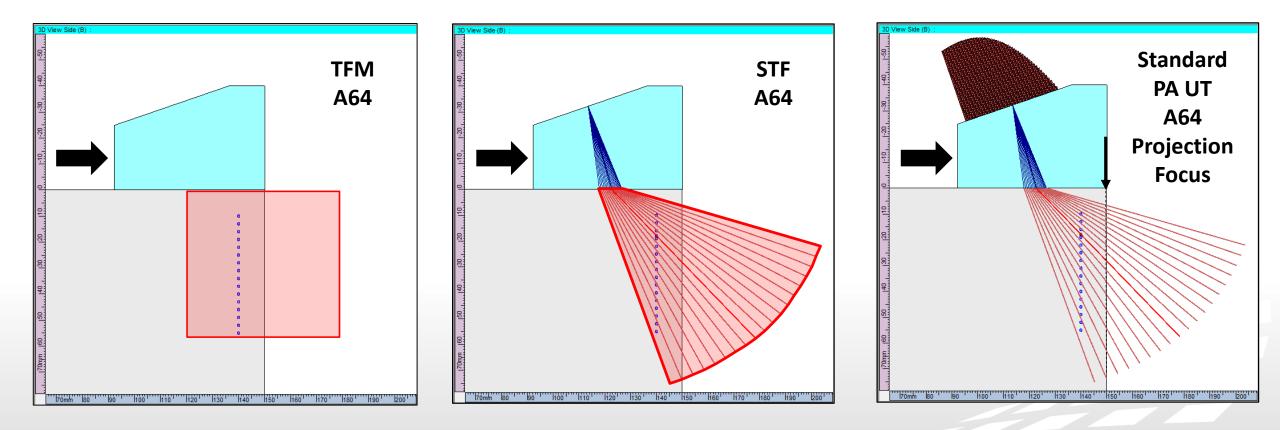


Benefits of Advanced Focusing Techniques ZETEC 5 MHz linear array, 64 elements, LW wedge on Ø 1 mm SDH

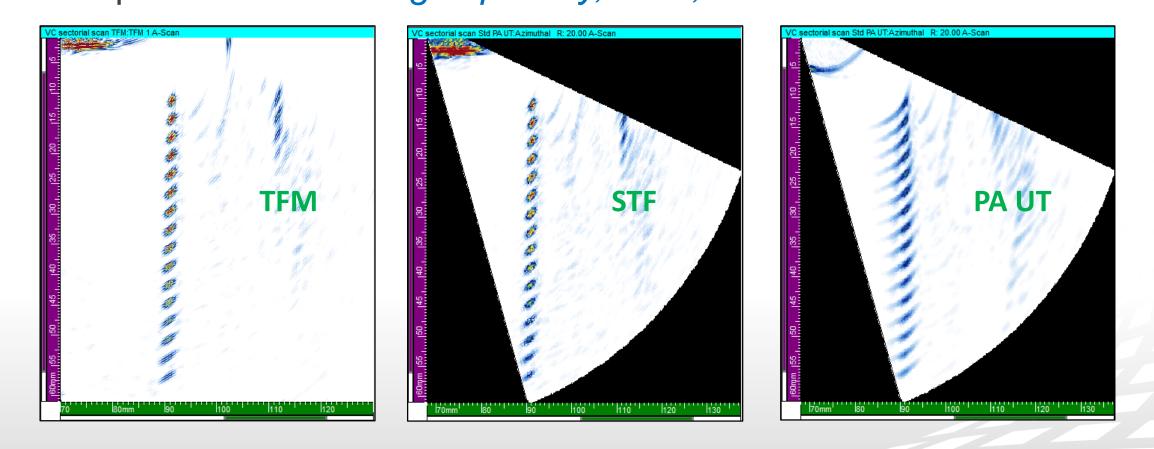
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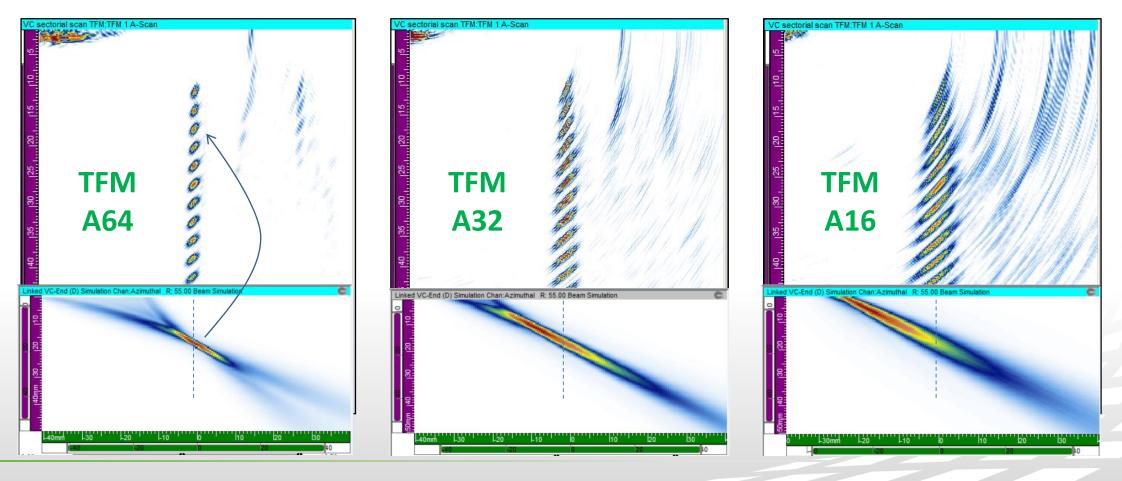
Benefits of Advanced Focusing Techniques ZETEC 5 MHz linear array, 64 elements, LW wedge on Ø 1 mm SDH Comparison of focusing capability, TFM, STF versus standard PA UT



Benefits of Advanced Focusing Techniques ZETEC 5 MHz linear array, 64 elements, LW wedge on Ø 1 mm SDH Comparison of *focusing capability, TFM, STF versus standard PA UT*



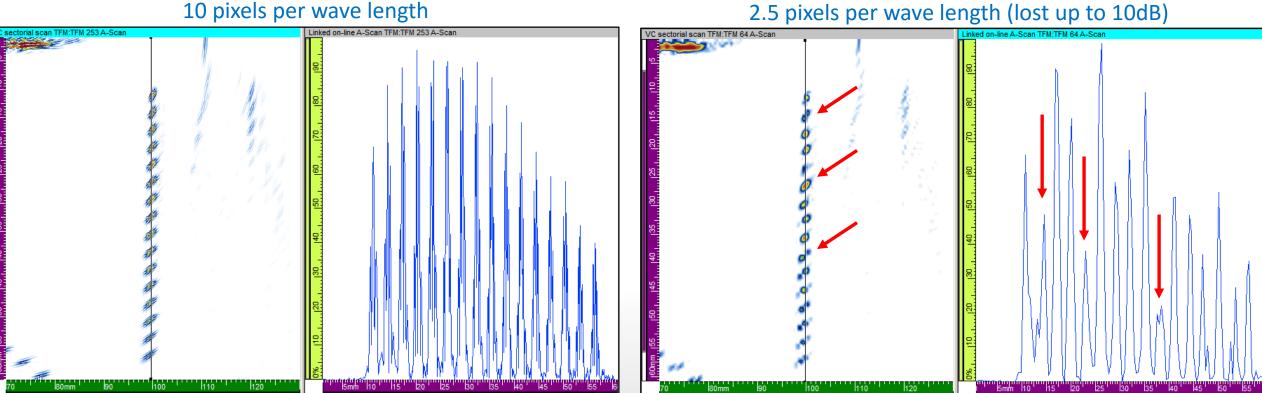
Benefits of Advanced Focusing Techniques ZETEC 5 MHz linear array, 64 elements, LW wedge on Ø 1 mm SDH Influence of active aperture on TFM focusing capability



Amplitude Fidelity – Impact on the Detection



5 MHz linear array, 64 elements, LW wedge on Ø 1 mm SDH Influence of the TFM frame resolution on detection (amplitude fidelity)



2.5 pixels per wave length (lost up to 10dB)

TFM Image Size version Resolution (Medium R -2dB)

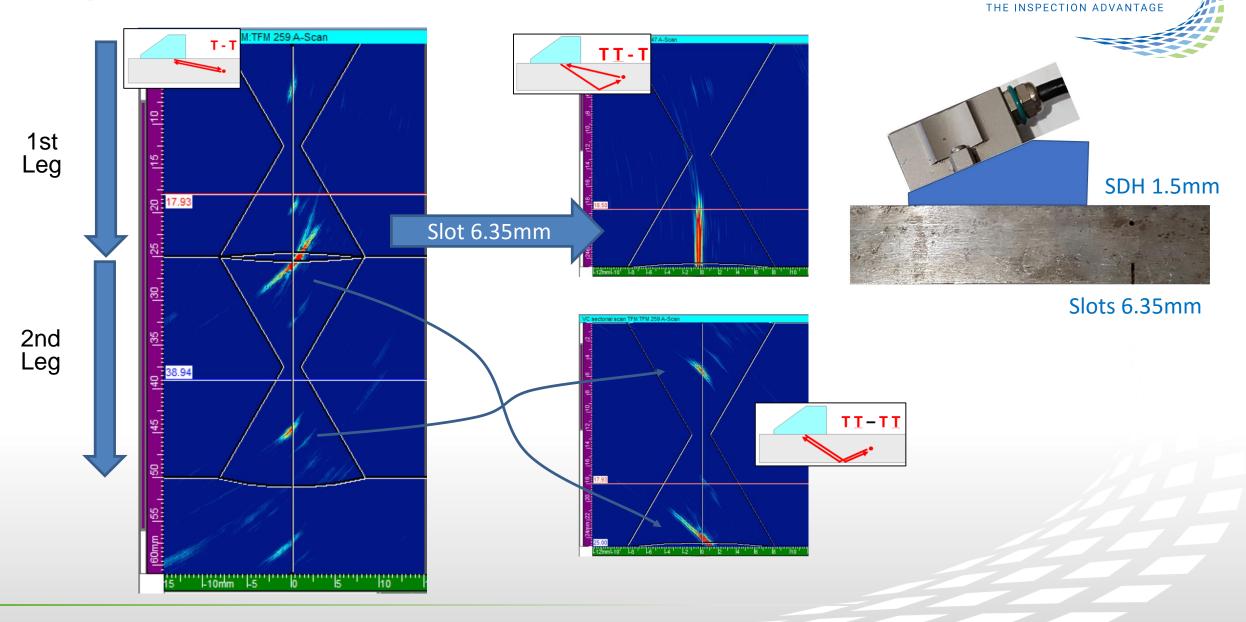


Frequency	5MHz, LW, Carbon Steel						
Pixels	256x	512x	1024x				
Application	HTHA, Corrosion, LW inspection Carbon Steel						
Frame	60mm	120mm	240mm				

For High Resolution (10 pixels/p, 0.5dB), thickness must be /2

Frequency	5MHz, SW, Carbon Steel						
Pixels	256x	512x	1024x				
Application	Weld Inspection, Carbon Steel, SW40 to 70						
Frame	33mm	66mm	132mm				

Inspection Modes



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Data Quantity & Offline Processing

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TFM – Data Quantity

Frame Size

- 256^{A2} pixels \rightarrow 65K points \rightarrow 128KB
- 512^{A2} pixels \rightarrow 262K points \rightarrow 0.5MB
- 1024^{A2} pixels \rightarrow 1M points \rightarrow 2MB

HMC (half FMC)

• 32.5MB

Linear Scanning, 64E aperture 10 Elements, A-Scan 1024 points

• 110KB

Sectorial Scanning, 40 to 70 res 1 deg, A-Scan 1024 points

• 62KB

Pipe 12", dual side, res.

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- 122MB
- 498MB
- 3.7GB

• 60.8GB

• 105MB

• 59MB

FMC Data & Offline processing



UV3 allows the FMC data processing, in the objective to

- Generate new TFM data (channel) with
 - Higher image resolution
 - \circ Alternative mode
 - o New specimen shape,
 - New material velocity
- Generate "standard" PA channels, for evaluating

Inspection Method, (Impact of detection/sizing according to PA parameters)
 Impact of dead elements



TFM – Codes

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Codes

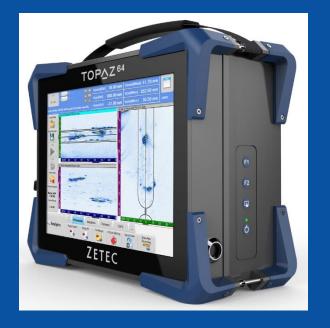


- Currently, this new methodology is **not supported** by Codes
- It is not permitted to use this technique for "Code compliant" inspections
- 2 working groups on FMC/TFM was founded
 - Zetec, other manufacturers, users and authorities are participating
 - Draft in progress
 - Issues to resolve

ASME Section V

- Schedule is to have a mandatory appendix for publication by December 2019
 IW, ISO codes
- Schedule is to have a code for September 2020
- The content, rules, should be as the ASME code, but under the ISO form.





TOPAZ 64

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TOP^AZ⁶⁴



- 64/128PR configuration for *two-side inspection of thick welds, with 64 active elements* + 2 separate conventional PE/TOFD channels at 200 V
- Magnesium casing, No air intake,
- 12" Hi-Res multi-touch display, 1024 x 768 pixels
- Windows 7 64 bits Ultimate
- SSD 512 GB
- Fast Ethernet, USB3, HDMI



TOP^AZ⁶⁴



- *"Live" TFM*, with frames 65k (256^2),
- Option *Live*" *TFM High Resolution*, with frames up to 1 *MB pixels* (1024^{^2}),
- Multi-groups, with TFM multi-modes
- Recording of TFM data groups,
- Option for recording FMC data on the fly
- 3 Encoders
- Driven by UltraVision Touch



Unipolar 75Vp or Bipolar 150Vpp, +40% acoustic energy *"Duty Cycle Control"*

75Vp

1:22

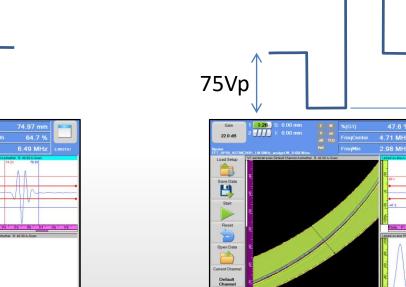
Save Da

Defaul

-95.0 %

EMITTER

Emission pulse stable, at the correct voltage (EN codes Code Compliance) in all cases (Pulse Width, Recurrence, Scanning speed, temperature)





150Vpp

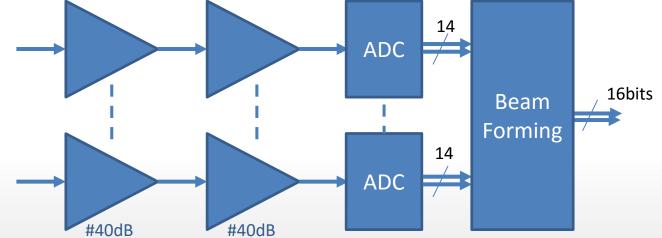






AMPLIFIER

- 2 Stages amplifier (per channel)
- 75 dB (Analog Gain)
- 14 bits ADC, 16 bits after beam forming (aperture 4E)



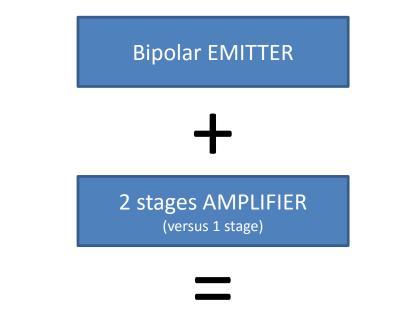








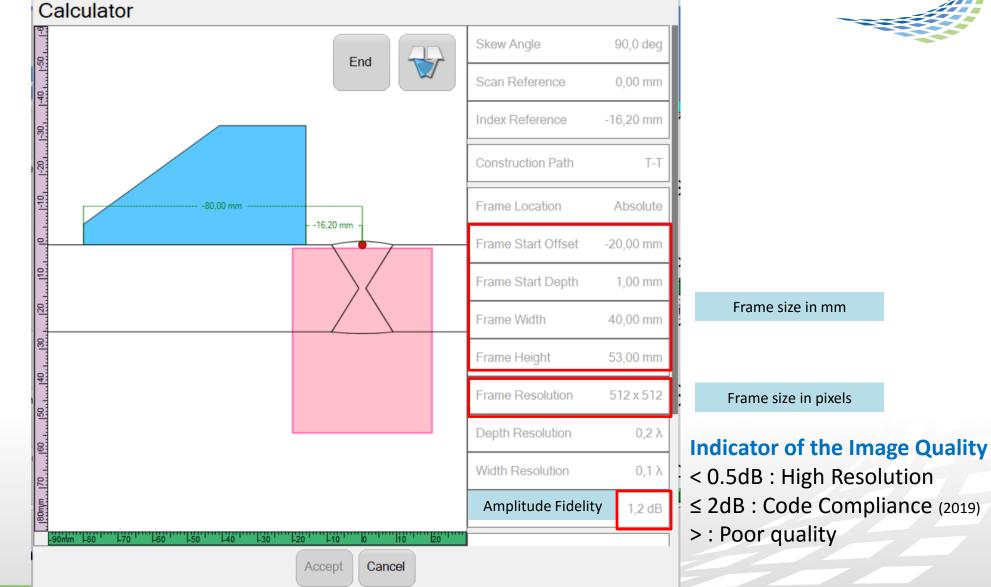




SNR Improvement from 12 to 18 dB

TOP²⁶⁴ - TFM Calculator

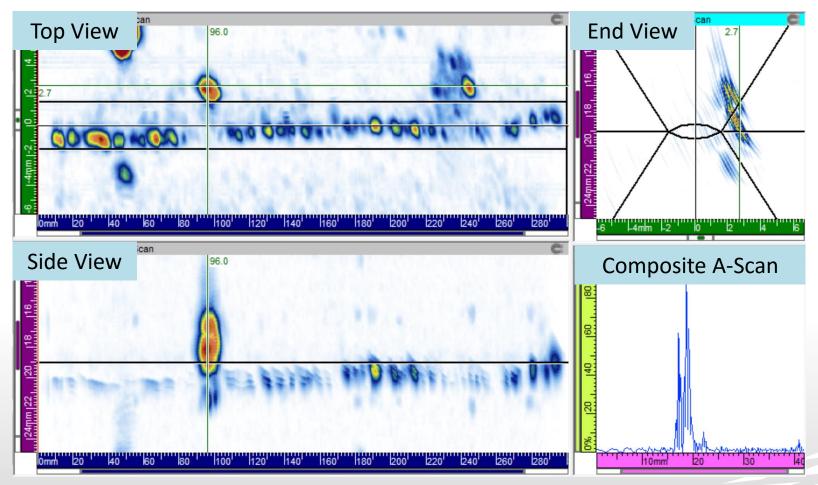




TOPAZ64 - Tools

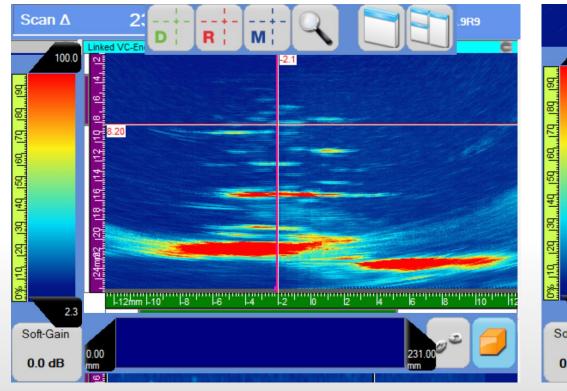


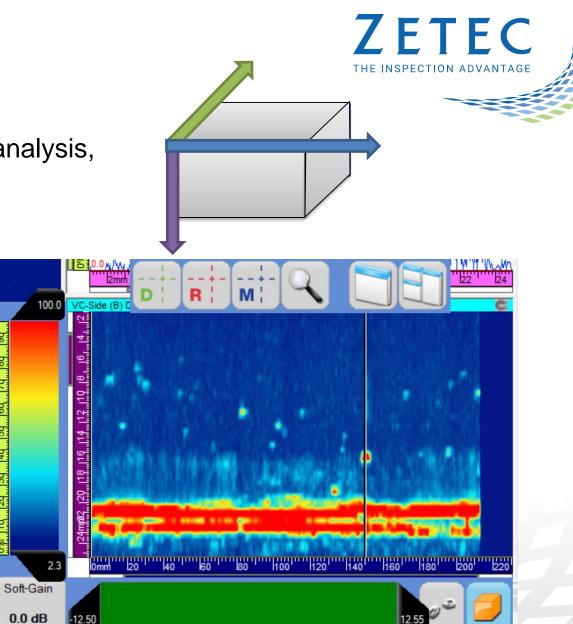
• All UT tools available for PA also available for TFM



TOPAZ64 - Tools

 Projection views with slicing cursors for quick analysis, Direct global view





TOP^Z64 - Configurations



Instrument model	Channel Configuration		FMC/TFM Resolution		Raw data saving	Multiple PA probes
	64/64	64/128	0.25M	1M		
ZPA-IUT-TOPAZ-64/64P	۷					V
ZPA-IUT-TOPAZ-64/64P-TFM	۷		۷			V
ZPA-IUT-TOPAZ-64/128PR		v				V
ZPA-IUT-TOPAZ-64/128PR-TFM		۷	۷			V
ZPA-IUT-TOPAZ-64/128PR-TFM HR		۷	۷	v		V
ZPA-IUT-TOPAZ-64/128PR-TFM HR-D		۷	۷	v	V	V





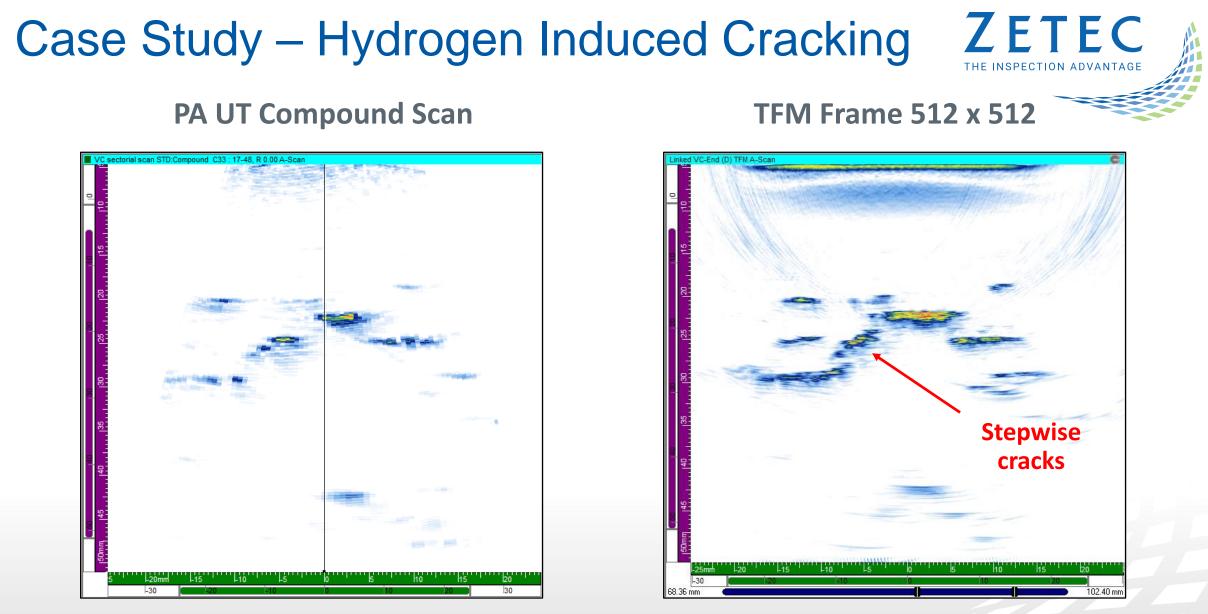
Case Study

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Case Study – HIC



- Hydrogen Induced Cracking (HIC), is a common type of damage occurring in wet H2S refinery process environments, even at relatively low temperatures.
- Specimen T = 1.5", with extensive HIC damage around mid-wall
 : hydrogen blisters connected by stepwise internal cracks
- 10 MHz linear array probe, 64 elements, in direct contact



(Courtesy of Lavender International)

Case Study – HTHA

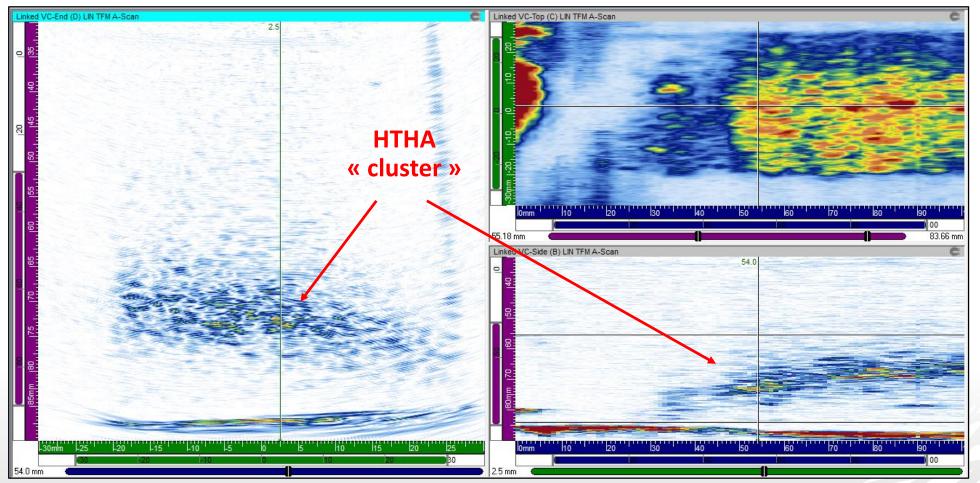


- High Temperature Hydrogen Attack, or HTHA, occurs in steels operating at high temperatures (above 400°F) in hydrogen environments, in refinery, petrochemical and chemical facilities
- Early stages of HTHA are difficult to detect, because of the small size of the voids, typically < 0.1 mm (0.004")
- Specimen contains HTHA damage around 3" deep
- 10 MHz linear array probe, 64 elements, in direct contact

Case Study – HTHA



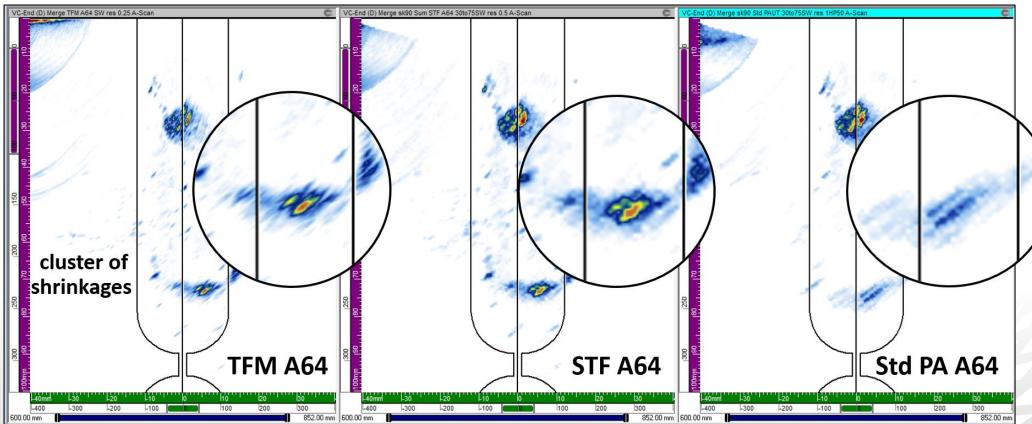
TFM Frame 512 x 512



(Courtesy of Lavender International)

Case Study – Thick CS Vessel Weld

5 MHz, 64 elements, SW wedge on thick vessel weld with real flaws Superior imaging and flaw characterization using TFM and STF



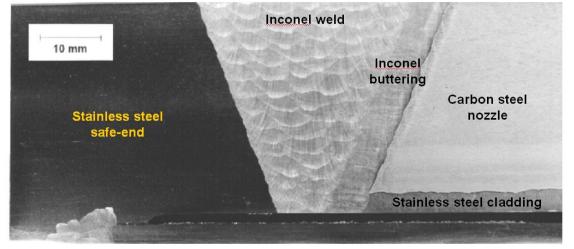
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Case Study – Dissimilar Metal Weld

- Dissimilar metal welds typically join two or more different materials, and mostly involve Inconel Alloys
- Often used to connect cladded carbon steel vessels to stainless steel piping
- Very challenging configurations for UT examination : propagation issues in austenitic structures, presence of multiple acoustic interfaces and sometimes very complex geometry (nozzles, tapers)
- In the late 1990's, primary water stress corrosion cracking (PWSCC) was encountered in nuclear plants all over the world, and led to development, qualification and on-site deployment of advanced PA UT inspection procedures

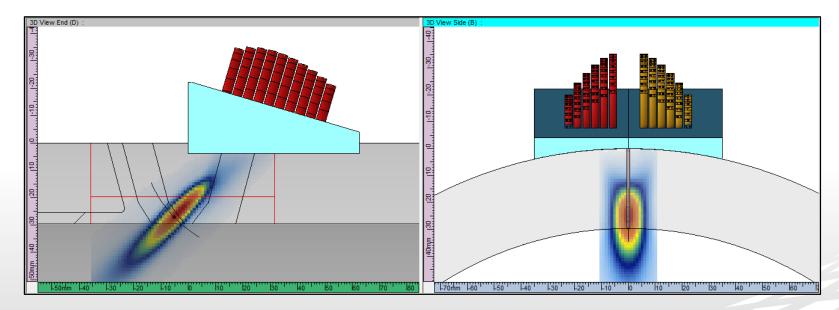






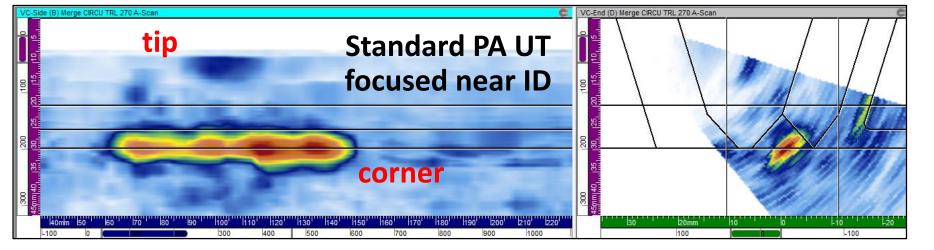
Case Study – Dissimilar Metal Weld

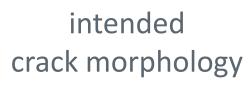
- ZETEC THE INSPECTION ADVANTAGE
- Inspection technique : 1.5 MHz DMA probe, 2 x (10x6), TRL mode
- T/R configuration offers better sensitivity and SNR, and avoids "ghost echoes" caused by internal wedge reflections
- DM weld specimen, T = 1.2", containing large ID crack

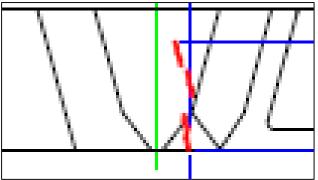


Case Study – Dissimilar Metal Weld

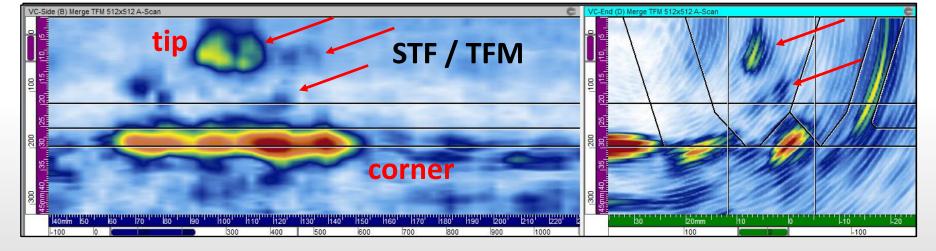








(Courtesy of EPRI and Nucleom)





Case Studies

Weld Inspection CS (Basic)

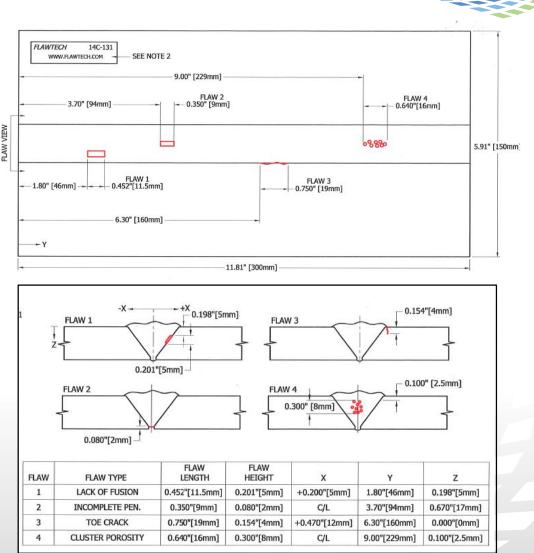
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Carbon Steel Plate Weld

Carbon steel plate weld (T = 0.75"), with realistic welding defects

Linear array LM 5 MHz (64 elements) on 55SW wedge

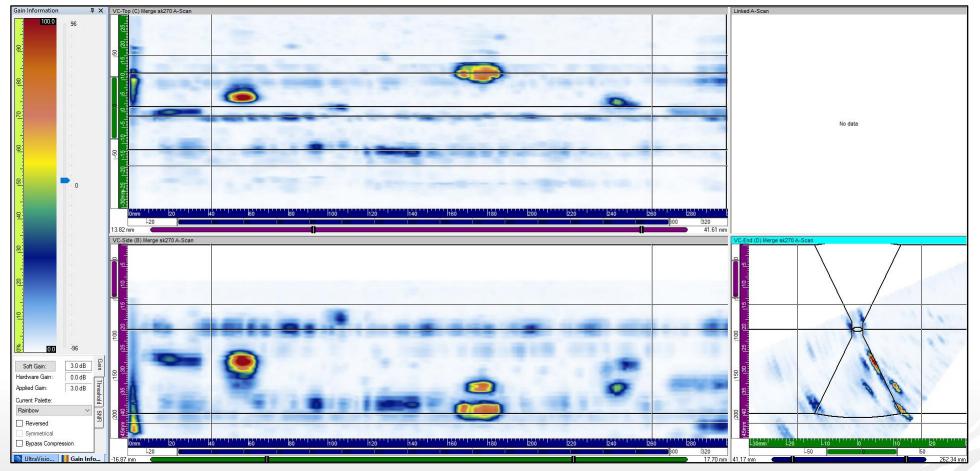
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Merged Data, Standard PA

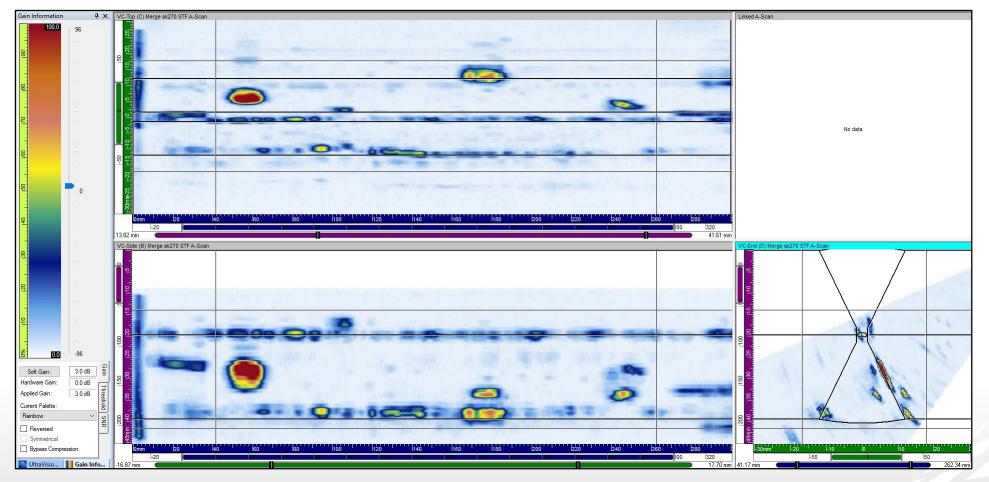




Merged data, from Standard PA Sector 40 to 70 SW, focusing at HP 50 mm, skew 270: LOF, Incomplete Penetration, Toe Crack and Porosity visible on End View

Merged Data, STF

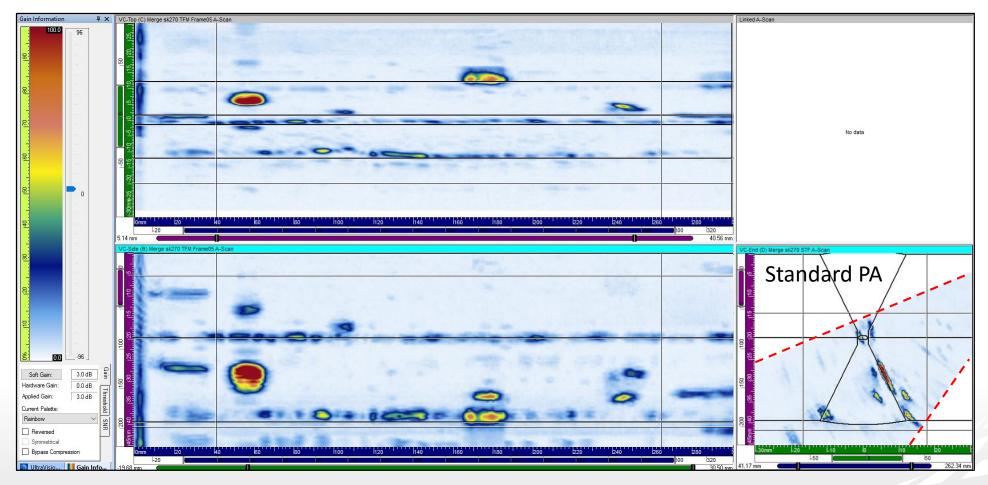




Merged data, from Reconstructed STF 40 to 70 SW, skew 270 : LOF, Incomplete Penetration, Toe Crack and Porosity visible on End View

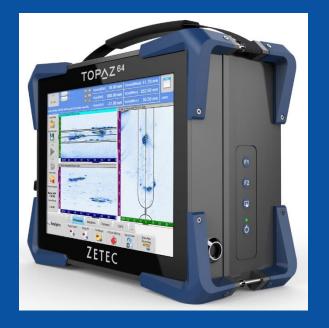
Merged data, TFM





Merged data, from reconstructed TFM frames SW, skew 270 : LOF, Incomplete Penetration, Toe Crack and Porosity visible on End View





Conclusion

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Conclusions



- Advanced focusing techniques are a promising additional tool in the phased array UT toolkit, to improve resolution of flaw images, and inspection coverage
- Active aperture and frame resolution are key parameters for the TFM technique, and must be carefully selected to exploit full potential of the technique
- Careful probe selection (wave mode, frequency) & probe position remains a requirement for succes
- In the framework of regulated inspections, code-compliant PA UT and TOFD techniques can be complemented with TFM for flaw characterization
- TOP⁵Z⁶⁴ offers industrially proven PA UT and TOFD, and high-resolution live TFM, in a single portable phased array unit.

TOP^Z Product Family





Portable Value Ideal for common inspections

TOP^AZ³²

Portable Performance Ideal for challenging inspections



TOP^AZ⁶⁴

Portable Intelligence For the most challenging inspections

a TOPAZ for every application !